FORM PTO-1449
INFORMATION DISCLOSURE
STATEMENT BY APPLICANT(S)

Atty Docket No. Serial No.

: 1**2177/13401** :09/*900:*777

Inventors

: Michael K. BRAND et al.

Filed

: April 25, 2000

Group Art Unit

: 2128

Examiner

: Thai Q. PHAN

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DATE CONSIDERED

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Atty Docket No.

: 12177/13401 : 60/0/0.77

Serial No. Inventors : 69/900,777 : Michael K. BRAND et al.

Filed :

: April 25, 2000

Group Art Unit

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Examiner

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